## TOSHIBA

Unit in mm

 $0.4{\pm}0.05$ 

4.2 MAX.  $2.5\pm0.$ 

0.8MIN.

+0.080.4 - 0.05

 $1.5\pm0.1$ 

2. COLLECTOR (HEAT SINK)

SC-62

2-5K1A

Type Name

1,6 MAX

4.6 MAX.

1.7 MAX.

 $+0.08 \\ 0.45 - 0.05$ 

+0.080.4-0.05

 $1.5 \pm 0.1$ 

1.

PW-MINI JEDEC EIAJ

TOSHIBA

Weight: 0.05g

MARKING

BASE

3. EMITTER

TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

## R N 6 0 0 6

MOTOR DRIVE CIRCUIT APPLICATIONS. POWER AMPLIFIER APPLICATIONS. POWER SWITCHING APPLICATIONS.

- With Built-in Bias Resistors
- Simplify Circuit Design
- Reduce a Quantity of Parts and Manufacturing Process
- Small Flat Package
- $P_{C} = 1 \sim 2W$  (Mounted on Ceramic substrate)
- Complementary to RN5006

EQUIVALENT CIRCUIT

γP

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
Collector-Base Voltage		VCBO	-10	V	
Collector-Emitter Voltage		VCES	-10	V	
Emitter-Base Voltage		VEBO	-6	V	
Collector Current	DC	IC	-2	A	
	Pulse (Note1)	ICP	-4		
Base Current		IB	-0.4	Α	
Collector Power Dissipation		PC	500	mW	
Collector Power Dissipation		PC*	1000	mW	
Junction Temperature		Tj	150	°C	
Storage Temperature Range		$T_{stg}$	$-55 \sim 150$	°C	



\* : Mounted on ceramic substrate  $(250 \text{mm}^2 \times 0.8 \text{t})$ 

ELECTRICAL CHARACTERISTICS ( $Ta = 25^{\circ}C$ )

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Collector Cut-off Current	ICBO	$V_{CB} = -10V, I_E = 0$		_	-0.1	μA	
Emitter Cut-off Current	I <sub>EBO</sub>	$V_{EB} = -6V, I_C = 0$	-0.462	-0.60	-0.857	mA	
Collector-Emitter Breakdown Voltage	V(BR)CES	$I_{C} = -1mA$	-10	_		V	
DC Current Gain	h <sub>FE(1)</sub>	$V_{CE} = -1V, I_C = -0.5A$	160	—	600		
	h <sub>FE(2)</sub>	$V_{CE} = -1V, I_C = -4.0A$	60	_			
Collector-Emitter Saturation Voltage	V <sub>CE(sat)</sub>	$I_{C} = -2A, I_{B} = -0.05A$		_	-0.5	V	
Transition Frequency	$\mathbf{f}_{\mathbf{T}}$	$V_{CE} = -1V, I_C = -0.5A$		140	_	MHz	
Collector Output Capacitance	C <sub>ob</sub>	$V_{CB} = -10V, I_E = 0, f = 1MHz$		55	_	pF	
Resistor	R		7	10	13	kΩ	
961001EAA2							

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